



KERSEMI ELECTRONIC CO.,LTD.

# IRF1010NS IRF1010NL

- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated

D<sup>2</sup> Pak  
IRF1010NS

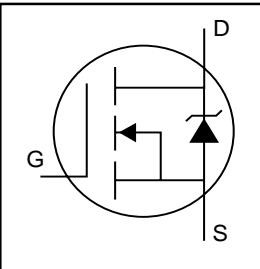
TO-262  
IRF1010NL



## Description

The D<sup>2</sup>Pak is a surface mount power package capable of accommodating die sizes up to HEX-4. It provides the highest power capability and the lowest possible on-resistance in any existing surface mount package. The D<sup>2</sup>Pak is suitable for high current applications because of its low internal connection resistance and can dissipate up to 2.0W in a typical surface mount application.

The through-hole version (IRF1010NL) is available for low-profile applications.



$V_{DSS} = 55V$   
 $R_{DS(on)} = 11m\Omega$   
 $I_D = 85A\text{⑦}$

## Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ ⑧	85⑦	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ ⑧	60	
$I_{DM}$	Pulsed Drain Current ①⑧	290	
$P_D @ T_C = 25^\circ C$	Power Dissipation	180	
	Linear Derating Factor	1.2	W/ $^\circ C$
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$I_{AR}$	Avalanche Current①	43	A
$E_{AR}$	Repetitive Avalanche Energy①	18	mJ
$dv/dt$	Peak Diode Recovery dv/dt ③⑧	3.6	V/ns
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to + 175	$^\circ C$
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

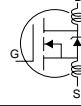
## Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	—	0.85	$^\circ C/W$
$R_{\theta JA}$	Junction-to-Ambient ( PCB Mounted,steady-state)**	—	40	

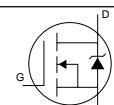


# IRF1010NS/IRF1010NL

## Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	55	—	—	V	$V_{\text{GS}} = 0\text{V}$ , $I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}/\Delta T_J}$	Breakdown Voltage Temp. Coefficient	—	0.058	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}$ , $I_D = 1\text{mA}$ ⑧
$R_{\text{DS}(\text{on})}$	Static Drain-to-Source On-Resistance	—	—	11	m $\Omega$	$V_{\text{GS}} = 10\text{V}$ , $I_D = 43\text{A}$ ④
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{\text{DS}} = V_{\text{GS}}$ , $I_D = 250\mu\text{A}$
$g_{\text{fs}}$	Forward Transconductance	32	—	—	S	$V_{\text{DS}} = 25\text{V}$ , $I_D = 43\text{A}$ ④ ⑧
$I_{\text{DSS}}$	Drain-to-Source Leakage Current	—	—	25	$\mu\text{A}$	$V_{\text{DS}} = 55\text{V}$ , $V_{\text{GS}} = 0\text{V}$
		—	—	250		$V_{\text{DS}} = 44\text{V}$ , $V_{\text{GS}} = 0\text{V}$ , $T_J = 150^\circ\text{C}$
$I_{\text{GSS}}$	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{\text{GS}} = 20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{\text{GS}} = -20\text{V}$
$Q_g$	Total Gate Charge	—	—	120	nC	$I_D = 43\text{A}$
$Q_{\text{gs}}$	Gate-to-Source Charge	—	—	19		$V_{\text{DS}} = 44\text{V}$
$Q_{\text{gd}}$	Gate-to-Drain ("Miller") Charge	—	—	41		$V_{\text{GS}} = 10\text{V}$ , See Fig. 6 and 13 ④ ⑧
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	—	13	—	ns	$V_{\text{DD}} = 28\text{V}$
$t_r$	Rise Time	—	76	—		$I_D = 43\text{A}$
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time	—	39	—		$R_G = 3.6\Omega$
$t_f$	Fall Time	—	48	—		$V_{\text{GS}} = 10\text{V}$ , See Fig. 10 ④ ⑧
$L_D$	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
$L_S$	Internal Source Inductance	—	7.5	—		
$C_{\text{iss}}$	Input Capacitance	—	3210	—	pF	$V_{\text{GS}} = 0\text{V}$
$C_{\text{oss}}$	Output Capacitance	—	690	—		$V_{\text{DS}} = 25\text{V}$
$C_{\text{rss}}$	Reverse Transfer Capacitance	—	140	—		$f = 1.0\text{MHz}$ , See Fig. 5 ⑧
$E_{\text{AS}}$	Single Pulse Avalanche Energy ② ⑧	—	1030 ⑤	250 ⑥	mJ	$I_{\text{AS}} = 4.3\text{A}$ , $L = 270\mu\text{H}$

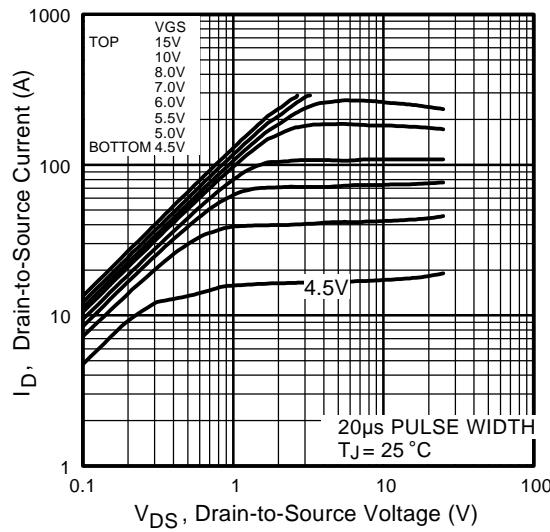
## Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	85 ⑦	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{\text{SM}}$	Pulsed Source Current (Body Diode) ①	—	—	290		
$V_{\text{SD}}$	Diode Forward Voltage	—	—	1.3	V	$T_J = 25^\circ\text{C}$ , $I_S = 43\text{A}$ , $V_{\text{GS}} = 0\text{V}$ ④
$t_{\text{rr}}$	Reverse Recovery Time	—	69	100	ns	$T_J = 25^\circ\text{C}$ , $I_F = 43\text{A}$
$Q_{\text{rr}}$	Reverse Recovery Charge	—	220	230	nC	$dI/dt = 100\text{A}/\mu\text{s}$ ④ ⑧
$t_{\text{on}}$	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S+L_D$ )				

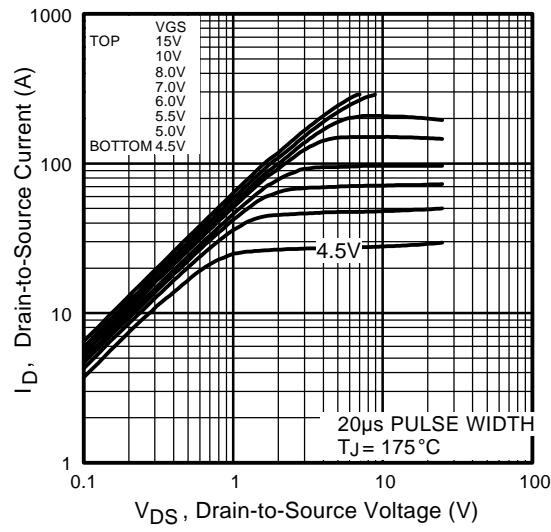
### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- ② Starting  $T_J = 25^\circ\text{C}$ ,  $L = 270\mu\text{H}$   
 $R_G = 25\Omega$ ,  $I_{\text{AS}} = 43\text{A}$ ,  $V_{\text{GS}}=10\text{V}$  (See Figure 12)
- ③  $I_{\text{SD}} \leq 43\text{A}$ ,  $dI/dt \leq 210\text{A}/\mu\text{s}$ ,  $V_{\text{DD}} \leq V_{(\text{BR})\text{DSS}}$ ,  
 $T_J \leq 175^\circ\text{C}$
- ④ Pulse width  $\leq 400\mu\text{s}$ ; duty cycle  $\leq 2\%$ .
- ⑤ This is a typical value at device destruction and represents operation outside rated limits.
- ⑥ This is a calculated value limited to  $T_J = 175^\circ\text{C}$  .
- ⑦ Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A.
- ⑧ Uses IRF1010N data and test conditions.

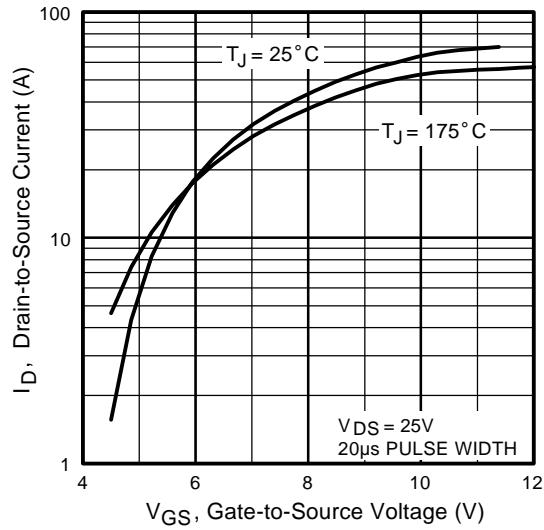
# IRF1010NS/IRF1010NL



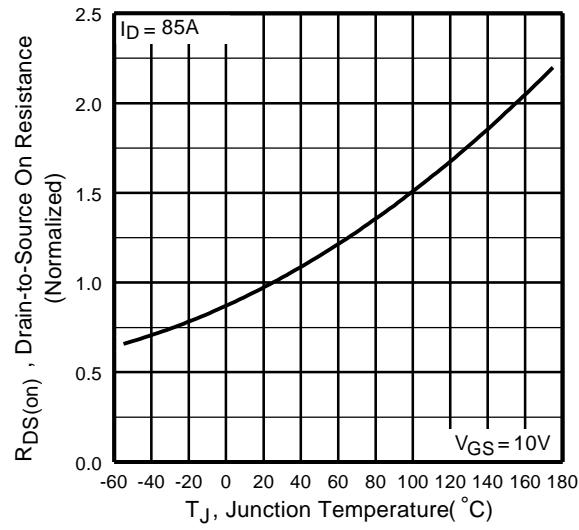
**Fig 1.** Typical Output Characteristics



**Fig 2.** Typical Output Characteristics

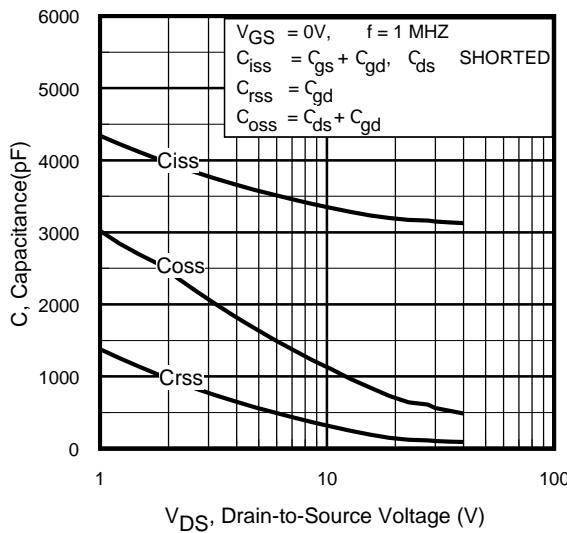


**Fig 3.** Typical Transfer Characteristics

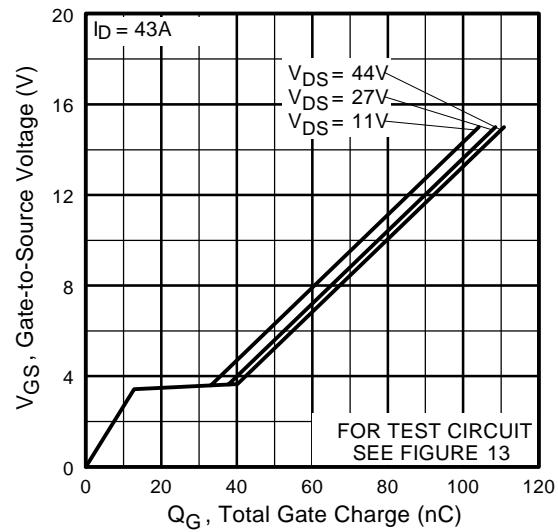


**Fig 4.** Normalized On-Resistance Vs. Temperature

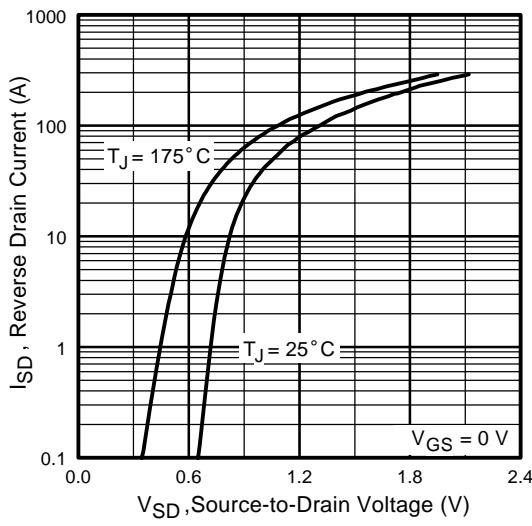
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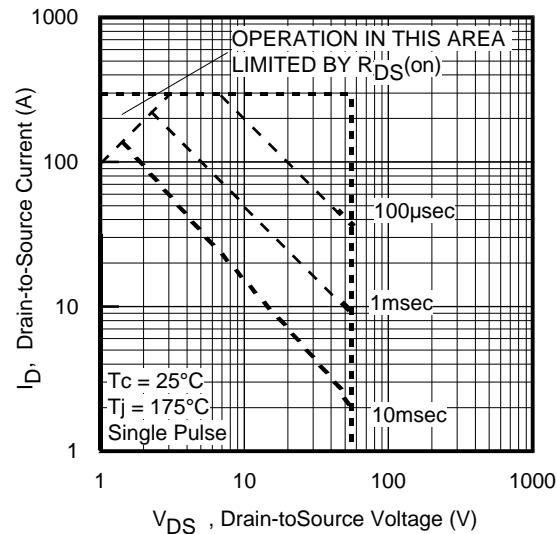
**Fig 5.** Typical Capacitance Vs.  
Drain-to-Source Voltage



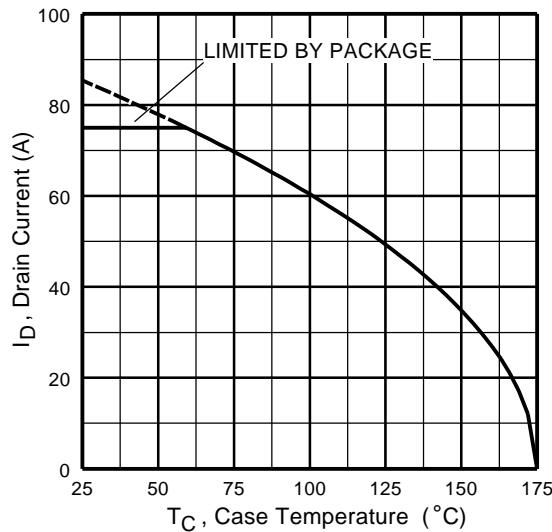
**Fig 6.** Typical Gate Charge Vs.  
Gate-to-Source Voltage



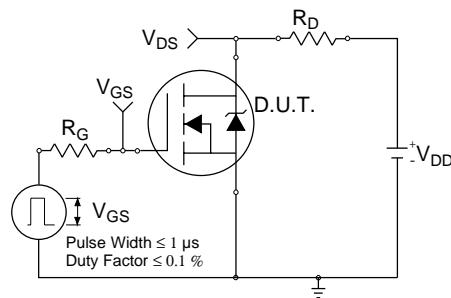
**Fig 7.** Typical Source-Drain Diode  
Forward Voltage



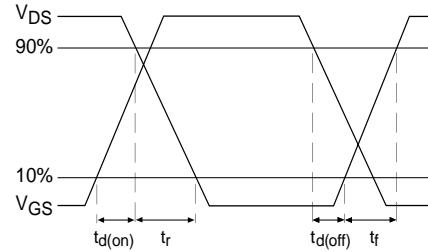
**Fig 8.** Maximum Safe Operating Area



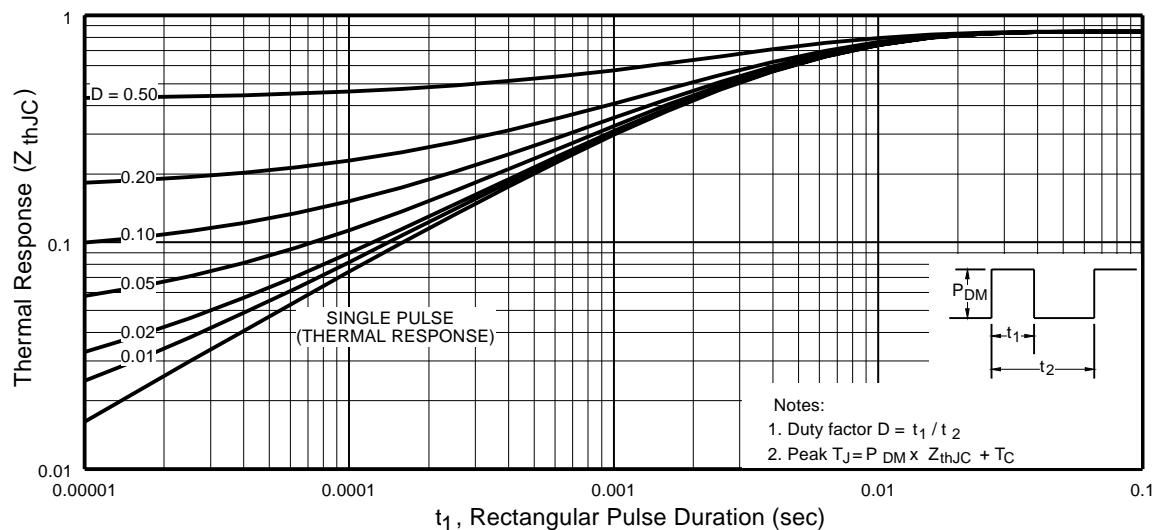
**Fig 9.** Maximum Drain Current Vs. Case Temperature



**Fig 10a.** Switching Time Test Circuit

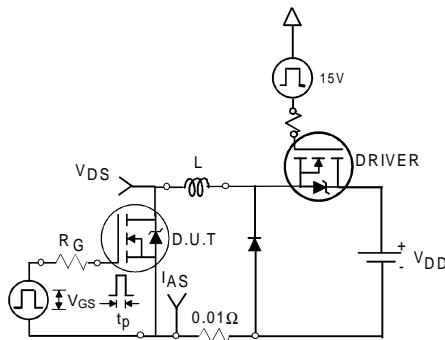


**Fig 10b.** Switching Time Waveforms

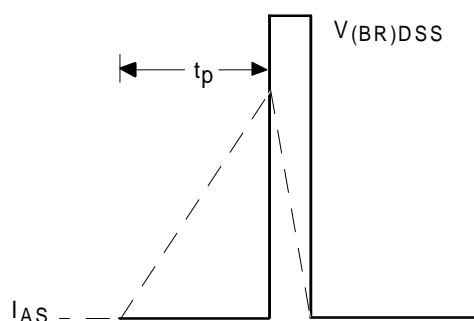


**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case

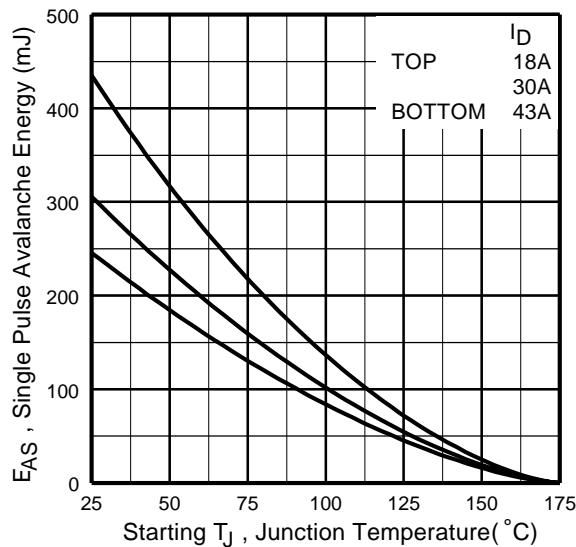
## IRF1010NS/IRF1010NL



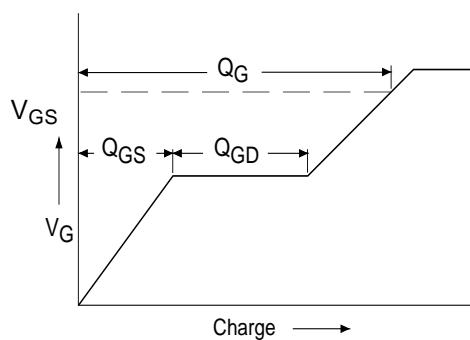
**Fig 12a.** Unclamped Inductive Test Circuit



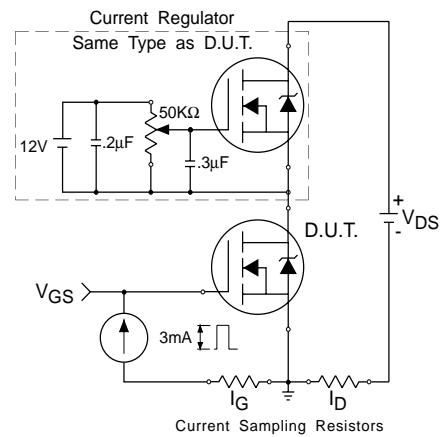
**Fig 12b.** Unclamped Inductive Waveforms



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current

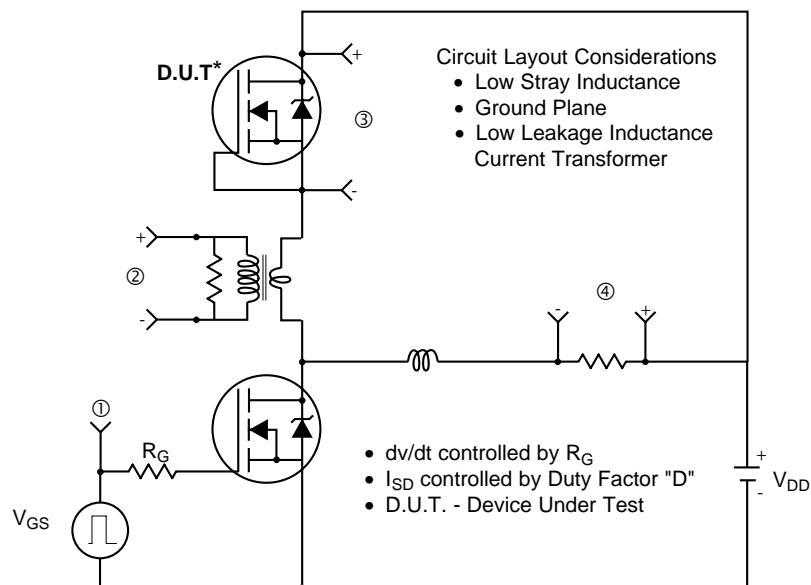


**Fig 13a.** Basic Gate Charge Waveform

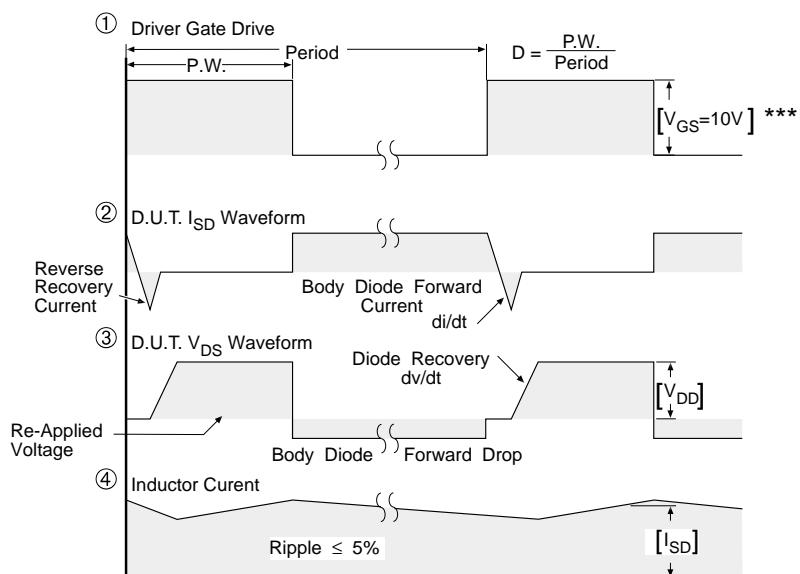


**Fig 13b.** Gate Charge Test Circuit

### Peak Diode Recovery dv/dt Test Circuit



\* Reverse Polarity of D.U.T for P-Channel

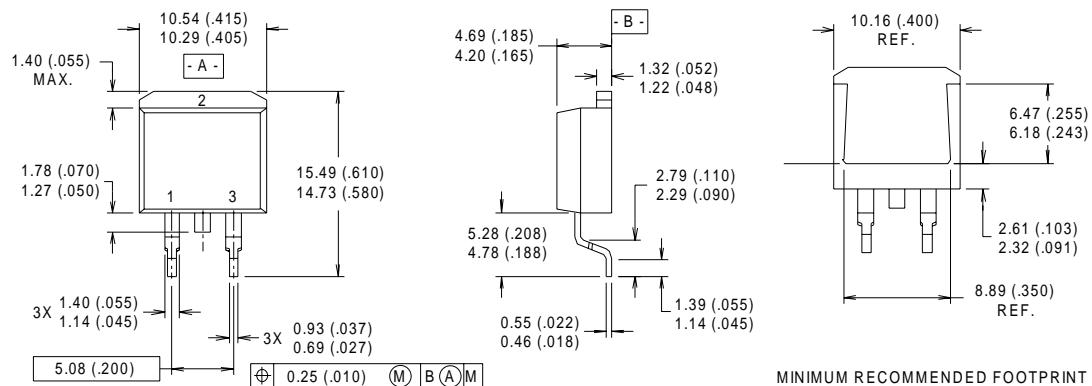


\*\*\*  $V_{GS} = 5.0V$  for Logic Level and 3V Drive Devices



# IRF1010NS/IRF1010NL

## D<sup>2</sup>Pak Package Outline



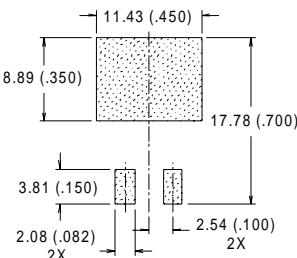
### NOTES:

- 1 DIMENSIONS AFTER SOLDER DIP.
- 2 DIMENSIONING & TOLERANCING PER ANSI Y14.5M, 1982.
- 3 CONTROLLING DIMENSION : INCH.
- 4 HEATSINK & LEAD DIMENSIONS DO NOT INCLUDE BURRS.

### LEAD ASSIGNMENTS

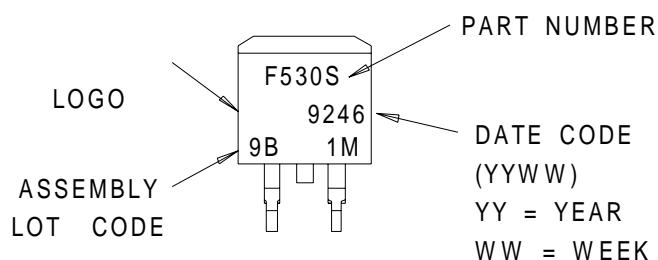
- 1 - GATE
- 2 - DRAIN
- 3 - SOURCE

### MINIMUM RECOMMENDED FOOTPRINT



## Part Marking Information

D<sup>2</sup>Pak

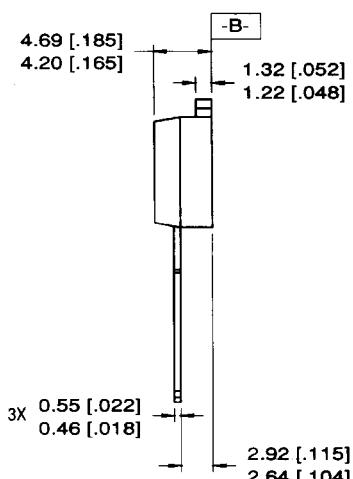
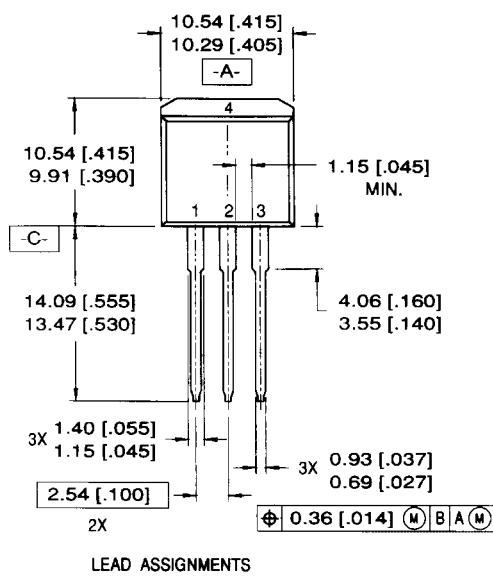




# IRF1010NS/IRF1010NL

## Package Outline

### TO-262 Outline



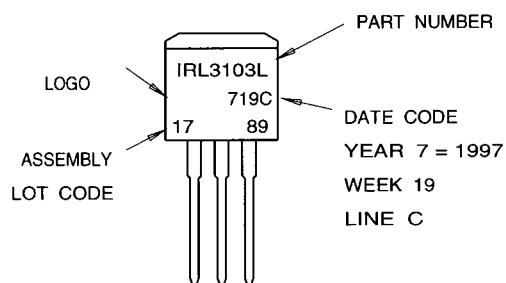
#### NOTES:

1. DIMENSIONING & TOLERANCING PER ANSI Y14.5M-1982
2. CONTROLLING DIMENSION: INCH.
3. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
4. HEATSINK & LEAD DIMENSIONS DO NOT INCLUDE BURRS.

## Part Marking Information

### TO-262

EXAMPLE: THIS IS AN IRL3103L  
 LOT CODE 1789  
 ASSEMBLED ON WW 19, 1997  
 IN THE ASSEMBLY LINE "C"





# IRF1010NS/IRF1010NL

## Tape & Reel Information D<sup>2</sup>Pak

